



IECQ QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L ULTW 16.0003-16	Issue No.:	1	Status:	Current
Additional Site to Certification: IECQ-L ULTW 16.0003 Originally Issued: 2016/07/28					
Supersedes:	Issue Date: 2024/09/03 Site Added: 2024/09/03				
CB Reference No.:	50600599 ITL	Expiration:	2025/07/27		

Materials Analysis Technology (SuZhou) Ltd.

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The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

The provision of materials analysis and failure analysis services of semiconductors.
See attached Schedule

-- Attached Schedule: IECQ-L_ULTW_50600599 ITL_09-03-24.pdf --

Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

8F, 23, Yuan Huan West Road,
Feng Yuan Dist., Taichung City
Taiwan

Authorized person:
Bob CHEN



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-16

CB Certificate No.: 50600599 ITL

Schedule Number: IECQ-L ULTW 16.0003-16-S Rev No.: 1 Revision Date: 2024/09/03 Page 1 of 1

Appendix-1 (50600599 ITL) Schedule of Scope to Certificate of Approval

Tests	Standards/Procedures
Scanning Electron Microscope (SEM)	T-SEM-3
EMMI-InGaAs	T-EFA-3
Focused Ion Beam Microscope (FIB)	T-FIB-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope	T-LAB-3
Chemical Treatment	T-LAB-3
2D X-Ray imaging	T-EFA-3
Optical Beam Induced Resistance Change (OBIRCH)	T-EFA-3
Scanning Acoustic Tomography (SAT)	T-EFA-3
THEMOS	T-EFA-3

Technical Reviewer of DQS:  Date: 9/3/2024

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